

54F/74F273 Octal D Flip-Flop

General Description

The 'F273 has eight edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset (\overline{MR}) inputs load and reset (clear) all flip-flops simultaneously.

The register is fully edge-triggered. The state of each D input, one setup time before the LOW-to-HIGH clock transition, is transferred to the corresponding flip-flop's Q output.

All outputs will be forced LOW independently of Clock or Data inputs by a LOW voltage level on the \overline{MR} input. The device is useful for applications where the true output only is required and the Clock and Master Reset are common to all storage elements.

Features

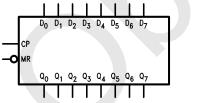
- Ideal buffer for MOS microprocessor or memory
- Eight edge-triggered D flip-flops
- Buffered common clock
- Buffered, asynchronous Master Reset
- See 'F377 for clock enable version
- See 'F373 for transparent latch version
- See 'F374 for TRI-STATE® version
- Guaranteed 4000V minimum ESD protection

| Commercial | Military | Package Number | Package Description |
|-------------------|-------------------|-------------------|---|
| 74F273PC | | N20A | 20-Lead (0.300" Wide) Molded Dual-In-Line |
| | 54F273DM (Note 2) | J20A | 20-Lead Ceramic Dual-In-Line |
| 74F273SC (Note 1) | | M20B | 20-Lead (0.300" Wide) Molded Small Outline, JEDEC |
| 74F273SJ (Note 1) | | M20D | 20-Lead (0.300" Wide) Molded Small Outline, EIAJ |
| | 54F273FM (Note 2) | W20A | 20-Lead Cerpack |
| | 54F273LM (Note 2) | E20A | 20-Lead Ceramic Leadless Chip Carrier, Type C |

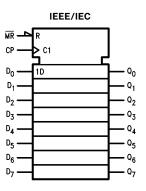
Note 1: Devices also available in 13" reel. Use suffix = SCX and SJX.

Note 2: Military grade device with environmental and burn-in processing. Use suffix = DMQB, FMQB and LMQB.

Logic Symbols



TL/F/9511-3

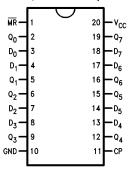


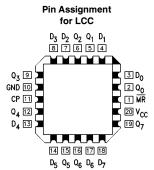
TL/F/9511-5

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Connection Diagrams

Pin Assignment for DIP, SOIC and Flatpak





TL/F/9511-2

TL/F/9511-1

Unit Loading/Fan Out

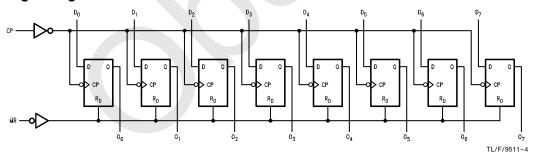
| | | 54F/74F | | | | |
|--------------------------------|--|------------------|---|--|--|--|
| Pin Names | Description | U.L. HIGH/LOW | Input I _{IH} /I _{IL} Output I _{OH} /I _{OL} | | | |
| D ₀ -D ₇ | Data Inputs | 1.0/1.0 | 20 μA/-0.6 mA | | | |
| MR | Master Reset (Active LOW) | 1.0/1.0 | 20 μA/-0.6 mA | | | |
| CP | Clock Pulse Input (Active Rising Edge) | 1.0/1.0 | $20 \mu A/-0.6 mA$ | | | |
| Q ₀ -Q ₇ | Data Outputs | 50/33.3 | -1 mA/20 mA | | | |

Mode Select-Function Table

| Operating Mode | | Output | | |
|----------------|----|--------|----|----|
| operating mode | MR | СР | Dn | Qn |
| Reset (Clear) | L | Х | Х | L |
| Load '1' | Н | | h | Н |
| Load '0' | Н | | ı | L |

- $\begin{array}{ll} H = HIGH\ Voltage\ Level\ steady\ state \\ h = HIGH\ Voltage\ Level\ one\ setup\ time\ prior\ to\ the\ LOW-to-HIGH\ clock \end{array}$ transition
- L = LOW Voltage Level steady state I = LOW Voltage Level one setup time prior to the LOW-to-HIGH clock

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

 $\begin{array}{lll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to } +125^{\circ}\mbox{C} \\ \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to } +175^{\circ}\mbox{C} \\ \mbox{Plastic} & -55^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \end{array}$

V_{CC} Pin Potential to

Voltage Applied to Output in HIGH State (with $V_{CC} = 0V$)

 $\begin{array}{lll} \text{Standard Output} & -0.5 \text{V to V}_{CC} \\ \text{TRI-STATE Output} & -0.5 \text{V to } +5.5 \text{V} \end{array}$

Current Applied to Output in LOW State (Max) twice the rated I_{OL} (mA) ESD Last Passing Voltage (min) 4000V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

Recommended Operating Conditions

Free Air Ambient Temperature

Supply Voltage

Military + 4.5V to + 5.5V Commercial + 4.5V to + 5.5V

DC Electrical Characteristics

| Symbol | Parameter | | 54F/74F | | | Units | V _{CC} | Conditions | |
|------------------|--------------------------------------|--|-------------------|-----|-------------------|--------|-----------------|--|--|
| Cymbol | | | Min | Тур | Max | Office | VCC | Conditions | |
| V_{IH} | Input HIGH Voltage | | 2.0 | | | V | | Recognized as a HIGH Signal | |
| V_{IL} | Input LOW Voltage | | | | 0.8 | V | | Recognized as a LOW Signal | |
| V_{CD} | Input Clamp Diode Vo | oltage | | | -1.2 | V | Min | $I_{IN} = -18 \text{ mA}$ | |
| V _{OH} | Output HIGH Voltage | Mil 10% V _{CC} 5% V _{CC} | 2.5 2.5 2.7 | | | v | Min | $I_{OH} = -1 \text{ mA}$ | |
| V _{OL} | Output LOW Voltage | Mil 10% V _{CC} 5% V _{CC} | | | 0.5 0.5 0.5 | ٧ | Min | I _{OL} = 20 mA | |
| I _{IH} | Input HIGH Current | 54F 74F | 7 | | 20.0 5.0 | μΑ | Max | $V_{IN} = 2.7V$ | |
| I _{BVI} | Input HIGH Current Breakdown Test | 54F 74F | | | 100 7.0 | μΑ | Max | V _{IN} = 7.0V | |
| I _{CEX} | Output HIGH Leakage Current | 54F 74F | | | 250 50 | μΑ | Max | V _{OUT} = V _{CC} | |
| V_{ID} | Input Leakage Test | 74F | 4.75 | | | V | 0.0 | $I_{\text{ID}} = 1.9 \mu\text{A}$ All other pins grounded | |
| I _{OD} | Output Leakage Circuit Current | 74F | | | 3.75 | μΑ | 0.0 | V _{IOD} = 150 mV All other pins grounded | |
| I _{IL} | Input LOW Current | | | | -0.6 | mA | Max | $V_{IN} = 0.5V$ | |
| los | Output Short-Circuit C | Current | -60 | | -150 | mA | Max | V _{OUT} = 0V | |
| I _{CCH} | Power Supply Current | t | | | 44 56 | mA | Max | $CP = \checkmark$ $D_n = \overline{MR} = HIGH$ | |

AC Electrical Characteristics

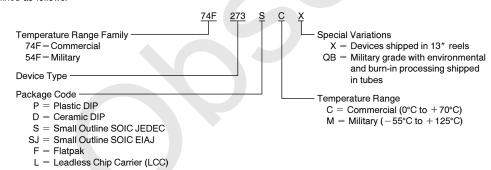
| | | 74F | | | 54F | | 74F | | |
|------------------|--------------------------------------|--|-----|-------------|--------------------------------------|-------------|--|------------|-------|
| Symbol Parameter | | $egin{array}{ll} T_{A}=+25^{\circ}C \ V_{CC}=+5.0V \ C_{L}=50\ pF \end{array}$ | | | T_A , $V_{CC} = Mil$ $C_L = 50 pF$ | | T _A , V _{CC} = Com C _L = 50 pF | | Units |
| | | Min | Тур | Max | Min | Max | Min | Max | |
| f _{max} | Maximum Clock Frequency | 160 | | | 95 | | 130 | | MHz |
| t _{PLH} | Propagation Delay Clock to Output | 3.0 4.0 | | 7.0 9.00 | 2.5 3.0 | 9.5 11.0 | 2.5 3.5 | 7.5 9.0 | ns |
| t _{PLH} | Propagation Delay MR to Output | 4.5 | | 9.5 | 3.0 | 11.0 | 4.0 | 10.0 | ns |

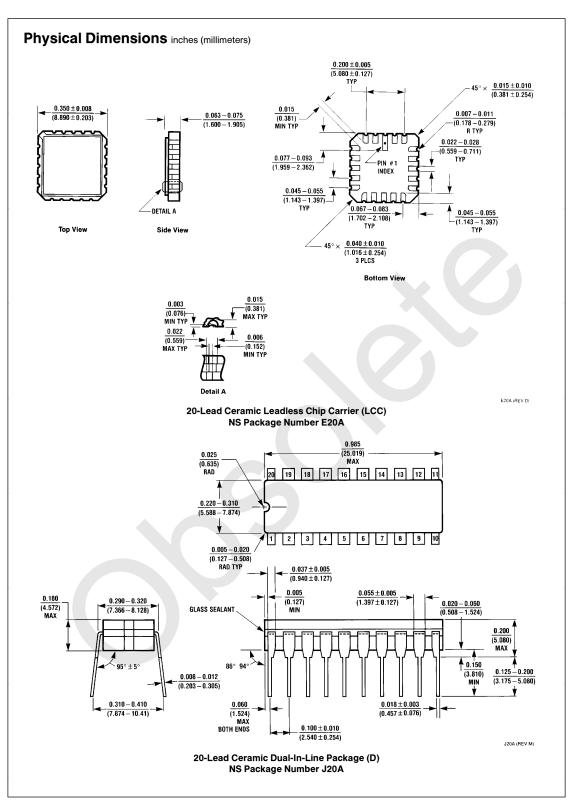
AC Operating Requirements

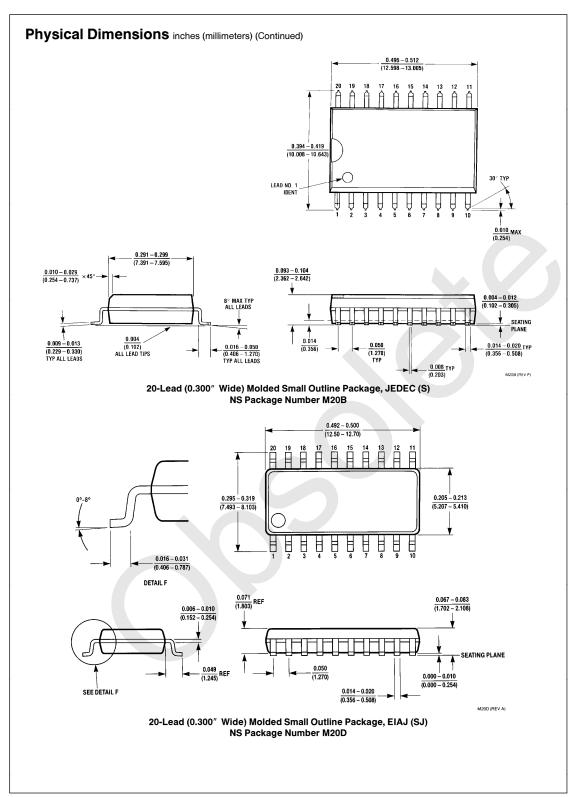
| | | $74F$ $T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ | | 54 | F | 74F T _A , V _{CC} = Com | | Units |
|--|---------------------------------------|---|-----|----------------------------------|-------|---|-----|-------|
| Symbol | Parameter | | | T _A , V _{CC} | = Mil | | | |
| | | Min | Max | Min | Max | Min | Max | |
| t _S (H) t _S (L) | Setup Time, HIGH or LOW Data to CP | 3.0 3.5 | | 3.5 4.0 | | 3.0 3.5 | | ns |
| t _h (H) t _h (L) | Hold Time, HIGH or LOW Data to CP | 0.5 1.0 | | 1.0 1.0 | | 0.5 1.0 | | 113 |
| t _w (L) | MR Pulse Width, LOW | 6.0 | | 4.0 | | 6.0 | | ns |
| t _w (H) t _w (L) | CP Pulse Width HIGH or LOW | 6.0 6.0 | | 5.0 5.0 | | 6.0 6.0 | | ns |
| t _{rec} | Recovery Time, MR to CP | 3.0 | | 4.5 | | 3.5 | | ns |

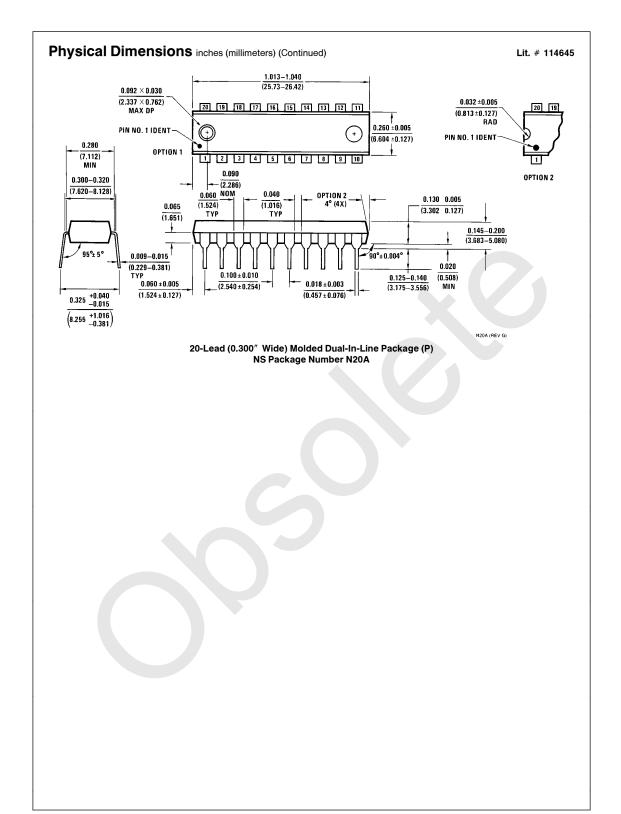
Ordering Information

The device number is used to form part of a simplified purchasing code where a package type and temperature range are defined as follows:

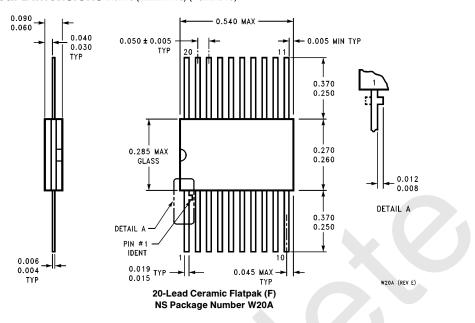








Physical Dimensions inches (millimeters) (Continued)



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National Semiconductor Corporation 2900 Semiconductor Drive P.O. Box 58090 Santa Clara, CA 95052-8090 Tel: 1(800) 272-9959 TWX: (910) 339-9240 National Semiconductor GmbH Livry-Gargan-Str. 10 D-82256 Fürstenfeldbruck Germany Tel: (81-41) 35-0 Telex: 527649 Fax: (81-41) 35-1 National Semiconductor Japan Ltd. Sumitomo Chemical Engineering Center Bldg. 7F 1-7-1, Nakase, Mihama-Ku Chiba-City, Ciba Prefecture 261

National Semiconductor Hong Kong Ltd. 13th Floor, Straight Block, Ocean Centre, 5 Canton Rd. Tsimshatsui, Kowloon Hong Kong Tel: (852) 2737-1600 Fax: (852) 2736-9960 National Semiconductores Do Brazil Ltda. Rue Deputado Lacorda Franco 120-3A Sao Paulo-SP Brazil 05418-000 Tel: (55-11) 212-5066 Telex: 391-1131931 NSBR BR Fax: (55-11) 212-1181

National Semiconductor (Australia) Pty, Ltd. Building 16 Business Park Drive Monash Business Park Nottinghilli, Melbourne Victoria 3168 Australia Tel: (3) 558-9999 Fax: (3) 558-9998